



A Novel Simulation Flow for 7nm Mixed-Signal Design Transistor Level Verification

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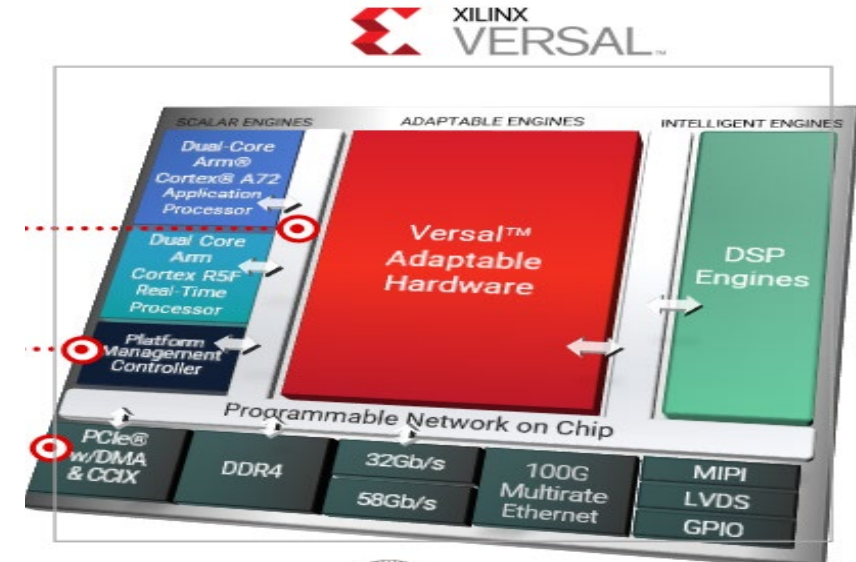
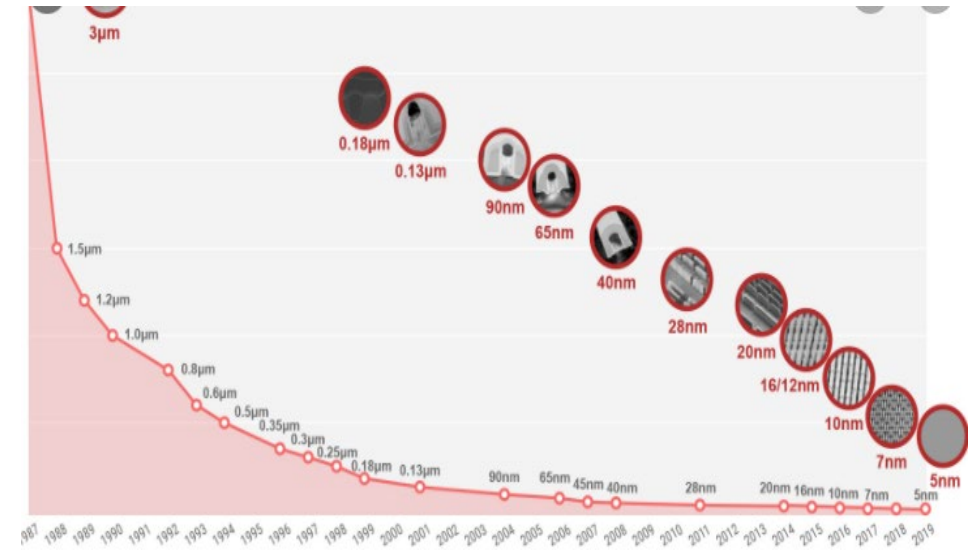
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Agenda

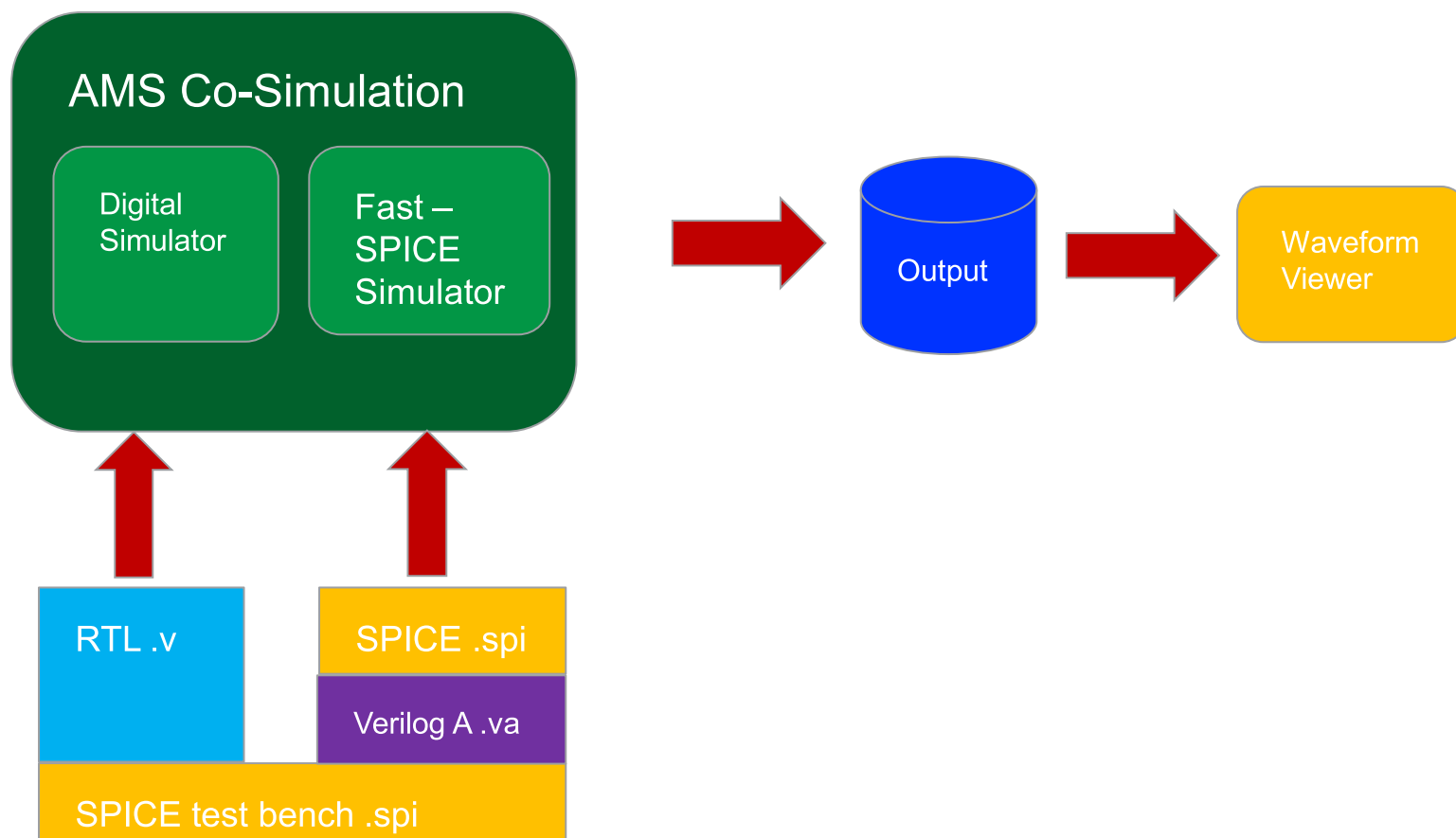
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7nm AMS Simulation Challenges

- Process technology continue to scale down
 - Advanced and complicated device models are required
 - Number of parasitic components increases
- More complexed chip
 - More function blocks integrated
 - Tighter design margins
 - Increased demand for design coverage
- AMS Simulation Flow Challenges
 - Longer turn around time
 - Requires larger simulator capacity
 - Demands more computation resources

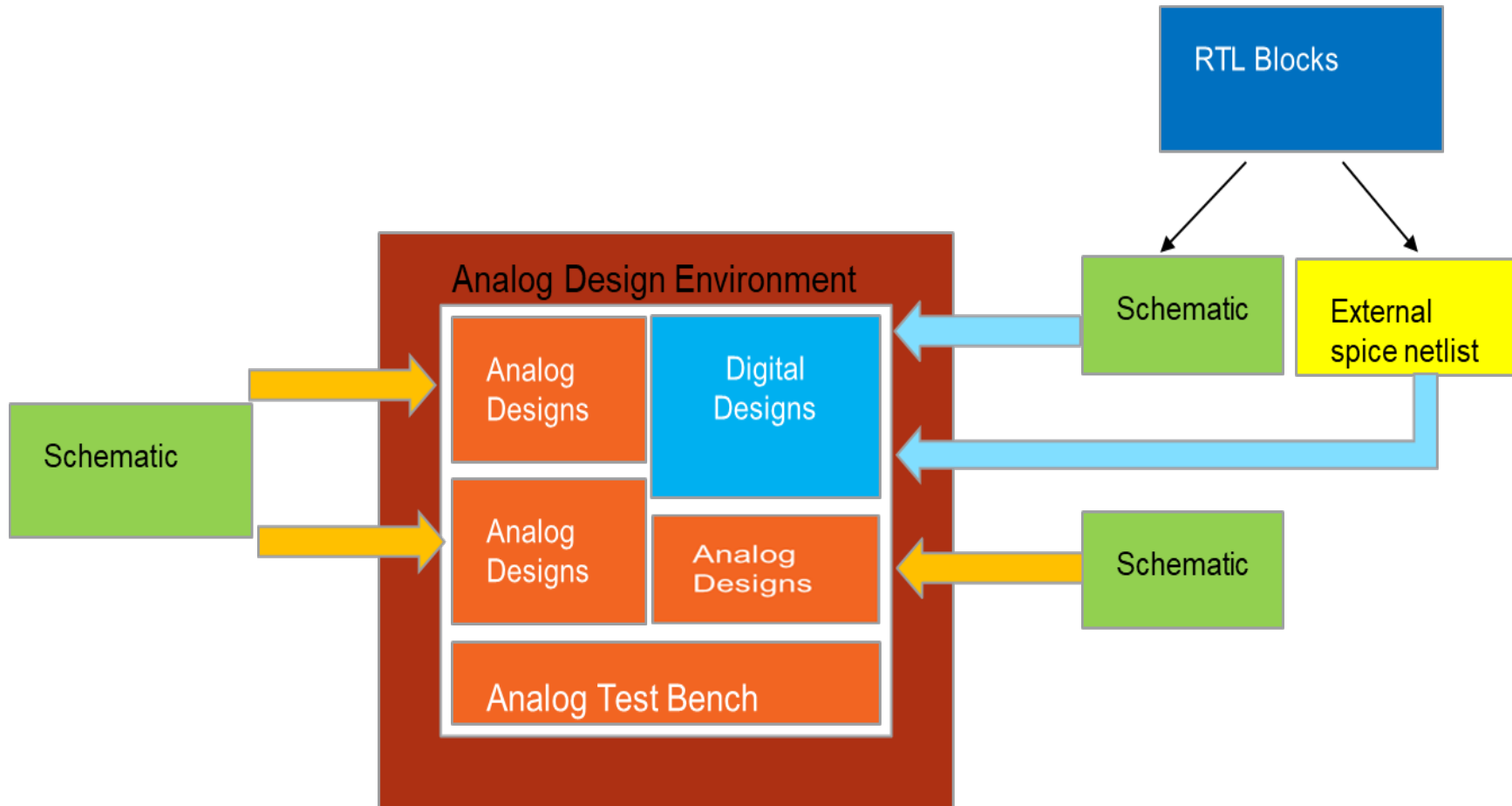


Xilinx/AMD Traditional AMS Simulation Flow and Issues



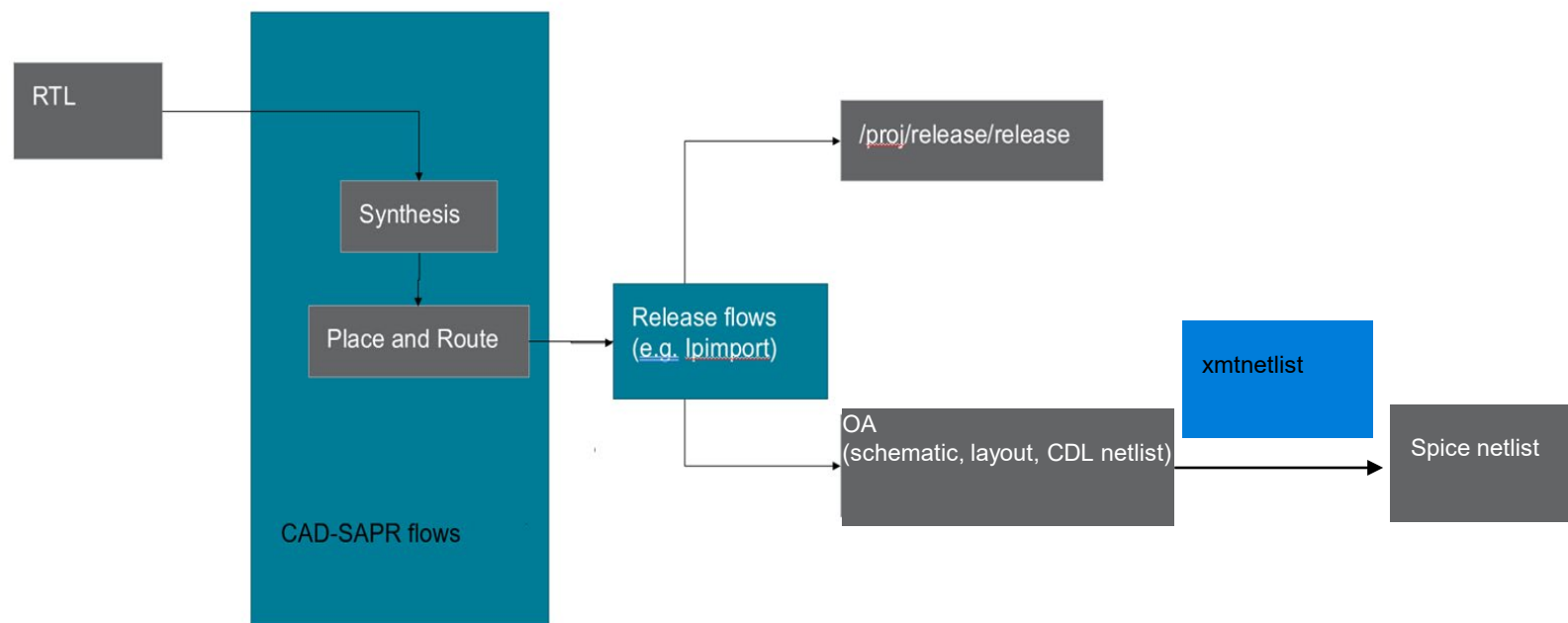
- Fast SPICE simulator can't achieve high accuracy required for high frequency components
- Switch between the command line-based environment for mixed-signal verification and the schematic based analog design environment.
- Need a new solution to speed up simulations time while maintaining good accuracy

New AMS Simulation Flow with RTL Blocks



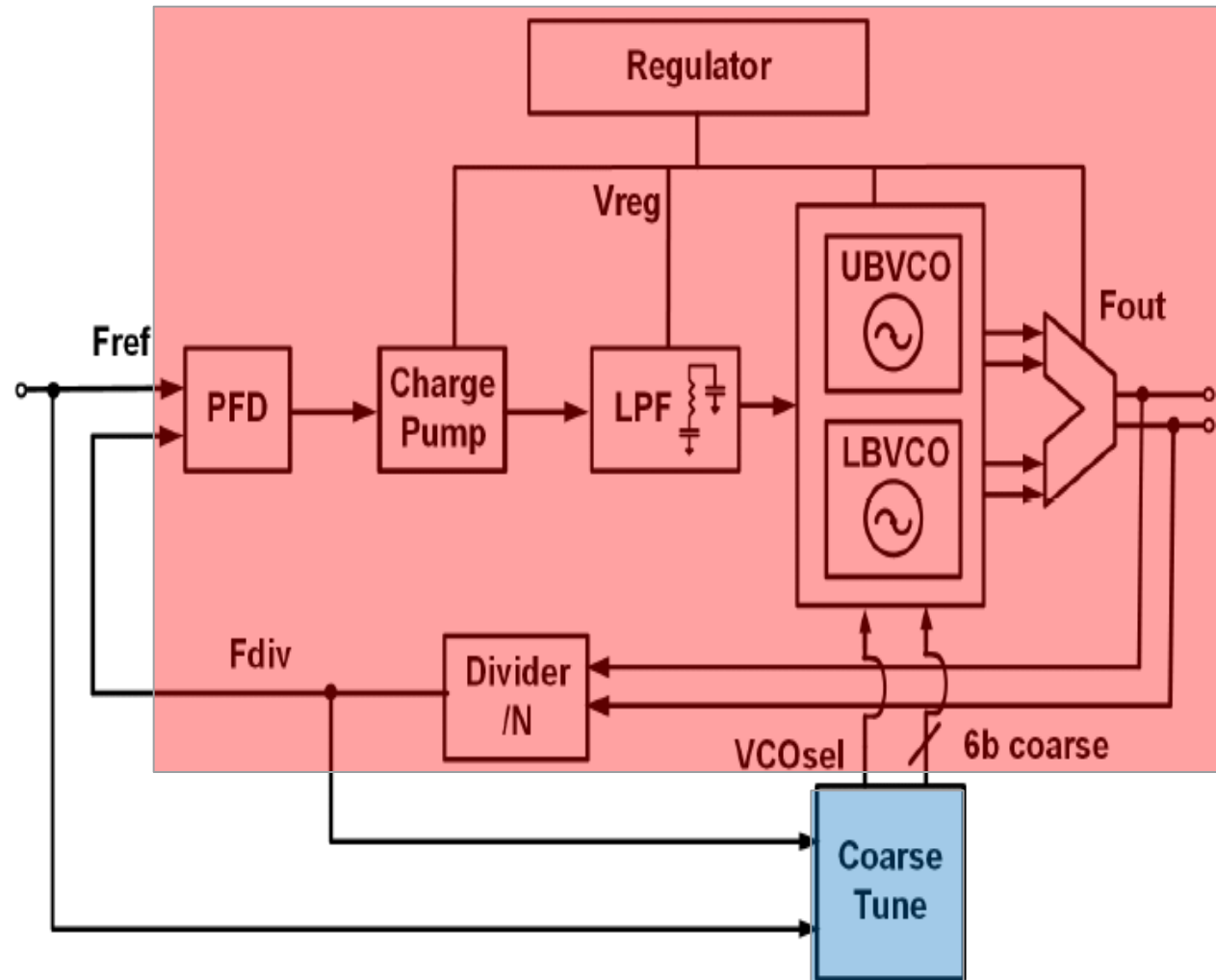
- Single environment for analog simulation and mixed-signal verification.
- Digital RTL is imported into schematic or an external SPICE file.
- High performance analog SPICE simulator is used to simulate both digital and analog blocks and deliver faster performance and better accuracy.

Importing RTL using Xilinx/AMD Digital IP Release Flow



- Digital IP assembled from RTL in a Synthesis, Place & Route (P&R) flow
- P&R tool writes design definition in Verilog, DEF, LEF
- Industry utility converts Verilog to CDL.
- Run the internal IP-import flow to enable downstream consumption
 - Stub verilog (pins only) imported to OA as stub schematic view
 - LEF imported to OA as stub layout view
- Special flow `xmtnetlist` to trace the hierarchy and build a suitable netlist, which is fed into the high-performance analog SPICE simulator.

Case Study: LCPLL Block Diagram



- Most challenging case in transistor level simulation.
- Slow PLL loop convergence requires simulation of long circuit time in the order of μs .
- VCO requires fine time step in the ps range due to its high frequency

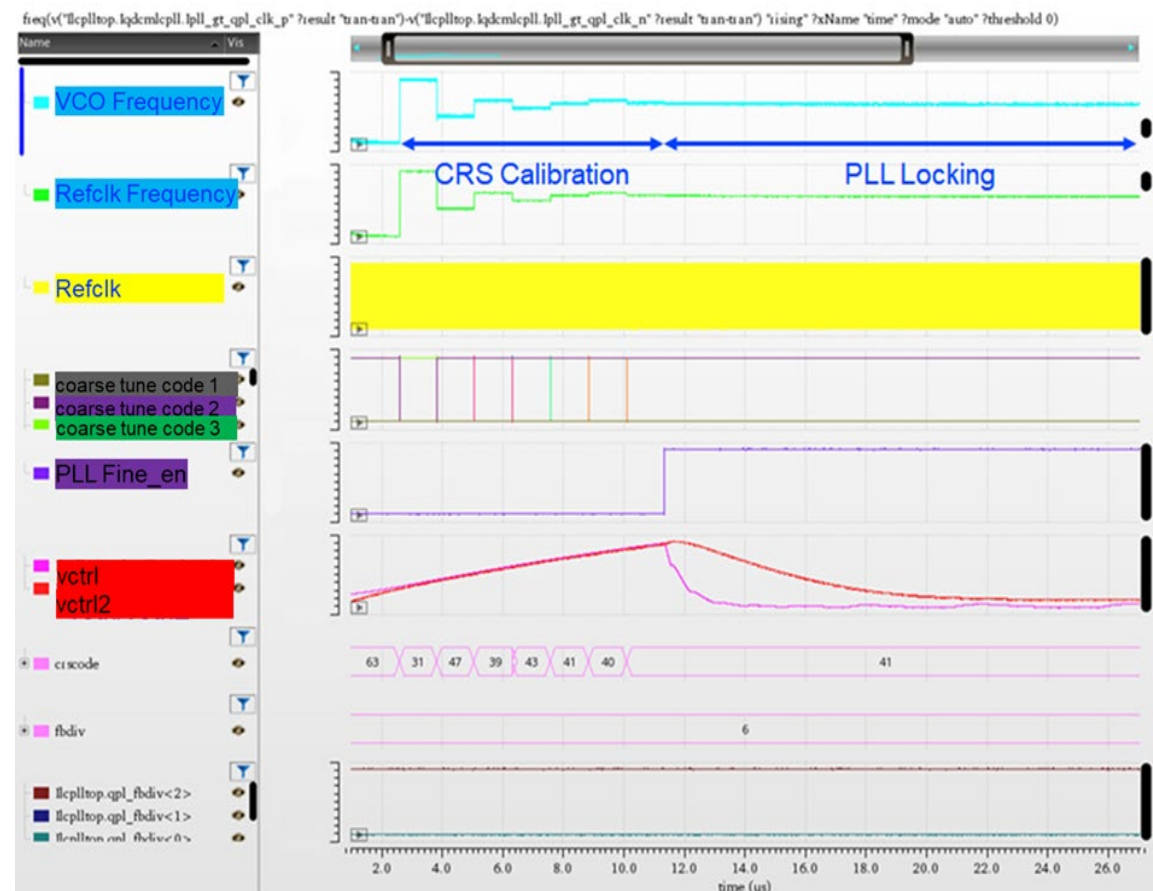
*D. Turker et al., "A 7.4-to-14GHz PLL with 54fsrms jitter in 16nm FinFET for integrated RF-data-converter SoCs," in Proc. IEEE Int. Solid-State Circuits Conf. (ISSCC) Dig. Tech. Papers, San Francisco, Feb. 2018, pp. 378–380.

Flow Setup and Results:

- Digital RTL code is imported into schematic and netlisted together with analog blocks.
- Top level test bench is imported from analog testbenches with customizations.
 - Import register settings from csv file
 - Optimize power up/down and reset sequence to speed up simulation
- Run simulation with parallel analog SPICE simulator in VX mode.
- Simulation results are verified using waveforms and measurement expressions.
- The simulation time is reduced from months to weeks, and the accuracy is sufficient for verification.

Simulation Results

- Circuit Inventory:
 - 1.28M Nodes, 334 K Transistors, 2.02M Capacitors, 1.0M Resistors.
- Simulation Time: 100 μ s
- Complete PLL simulation in 12 days from the initial coarse hunting phase to the fine vctrl set up phase
- The simulation captures different dynamics of the two phases
 - Phase 1: CRS Calibration
 - Coarse tuning of VCO frequency
 - Initial toggling of RTL code
 - vctrl1 and vctrl2 ramp up
 - Phase 2: PLL Locking
 - VCO frequency converges to reference clock frequency
 - RTL code stabilize
 - vctrl1 and vctrl2 settle



Conclusion

- A novel AMS simulation flow is presented using parallel analog SPICE simulator for mixed-signal functional verification for 7nm designs.
- Both block level simulation and top-level functional verification can be performed in the same environment, eliminating the need of switching design flows.
- This flow is proven efficient to detect potential bugs at early design phase. It reduces design cycle and provides confidence for final sign-off.

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